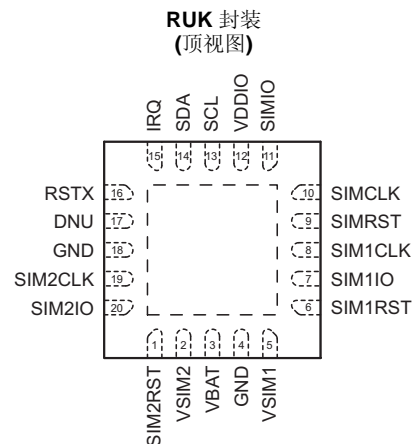


具有插槽专用双通道 LDO 的双电源 2:1 SIM 卡多路复用器/转换器

 查询样品: [TXS02324](#)

特性

- 平转换器
 - **VDDIO** 范围: **1.7V 至 3.3V**
- 低压降 (LDO) 稳压器
 - 带启用功能的 **50mA LDO** 稳压器
 - **1.8V 或 2.95V** 可选输出电压
 - **2.3V 至 5.5V** 输入电压范围
 - 超低压降: 在 **50mA** 电流条件下为 **100mV** (最大值)
- 通过 **I²C** 接口和基带处理器实现控制和通信
- **ESD** 保护等级超过了 **JESD 22** 规格的要求
 - **2000V** 人体模型 (**A114-B**)
 - **1000V** 充电器件模型 (**C101**)
- 封装
 - **20** 引脚 **QFN (3mm x 3mm)**



注: 裸露的散热衬垫必须连接至地。

说明/订购信息

TXS02324 是一款完整的双电源待机智能身份模块 (SIM) 卡解决方案, 用于将无线基带处理器与两个单独的 SIM 用户卡相连, 以存储移动手机应用程序的数据。这是一款定制器件, 用于把单个 SIM/UICC 接口扩展至能够支持两个 SIM/UICC (通用集成芯片卡)。

该器件遵循 ISO / IEC 智能卡接口要求以及 GSM 和 3G 移动标准。它包括一个能够支持 Class B (2.95V) 和 Class C (1.8V) 接口的高速电平转换器、两个具有可在 2.95V Class B 和 1.8V Class C 接口之间选择的输出电压的低压降 (LDO) 稳压器、一个用于配置的集成型“快速模式”400kb/s “从” I2C 控制寄存器接口、一个用于内部定时发生的 32kHz 时钟输入。

电压电平转换器具有两个电源电压引脚。VDDIO 引脚负责设定用于基带接口的基准, 并可采用 1.7V 至 3.3V 的工作电压。VSIM1 和 VSIM2 被设置为 1.8V 或 2.95V, 各由一个独立的内部 LDO 稳压器供电。集成型 LDO 可接受 2.3V 至 5.5V 的输入电池电压, 并向 B 侧电路及外部 Class B 或 Class C SIM 卡输出高达 50mA 的电流。

订购信息⁽¹⁾

T _A	封装 ⁽²⁾		可订购的器件型号	顶端标记
-40°C 至 85°C	QFN – RUK	卷带包装	TXS02324RUKR	ZUY

(1) 有关最新的封装和订购信息, 请参阅本文档结尾的“封装选项附录”, 或访问 TI 网站: www.ti.com.cn。

(2) 封装图样、热数据和符号可登录 www.ti.com/packaging 获取。



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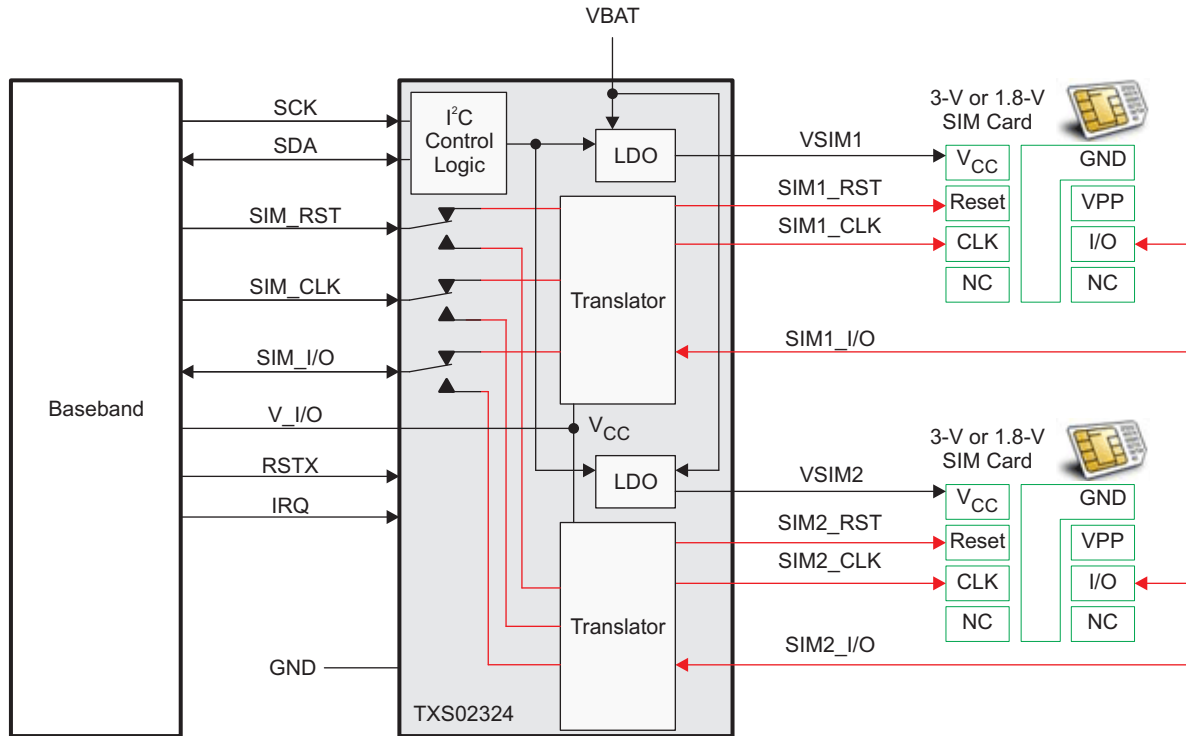


Figure 1. Interfacing With SIM Card

TERMINAL FUNCTIONS

NO.	NAME	TYPE ⁽¹⁾	POWER DOMAIN	DESCRIPTION
1	SIM2RST	O	VSIM2	SIM2 reset
2	VSIM2	O	VSIM2	1.8 V/2.95 V supply voltage to SIM2
3	VBAT	P	VBAT	Battery power supply
4	GND	G		Ground
5	VSIM1	O	VSIM1	1.8 V/2.95 V supply voltage to SIM1
6	SIM1RST	O	VSIM1	SIM1 reset
7	SIM1IO	I/O	VSIM1	SIM1 data
8	SIM1CLK	O	VSIM1	SIM1 clock
9	SIMRST	I	VDDIO	UICC/SIM reset from baseband
10	SIMCLK	I	VDDIO	UICC/SIM clock
11	SIMIO	I/O	VDDIO	UICC/SIM data
12	VDDIO	P	VDDIO	1.8-V power supply for device operation and I/O buffers toward baseband
13	SCL	I	VDDIO	I ² C clock
14	SDA	I/O	VDDIO	I ² C data
15	IRQ	I/O	VDDIO	Interrupt to baseband. This signal is used to set the I2C address.
16	RSTX	I	VDDIO	Active-low reset input from baseband
17	DNU	I	VDDIO	Do not use. Should not be electrically connected.
18	GND	G	-	GROUND
19	SIM2CLK	O	VSIM2	SIM2 clock
20	SIM2IO	I/O	VSIM2	SIM2 data

(1) G = Ground, I = Input, O = Output, P = Power

Table 1. Register Overview

REGISTER BITS								COMMAND BYTE (HEX)	REGISTER	READ OR WRITE	POWER-UP DEFAULT
B7	B6	B5	B4	B3	B2	B1	B0				
0	0	0	1	0	0	0	1	00h	Device hardware revision information	R	0001 0001
0	0	0	0	0	0	0	0	01h	Software revision information	R	0000 0000
SIM2 Interface Status		SIM1 Interface Status		Unused	Unused	Unused	Unused	04h	Status Register	R	0000 0000
SIM2 Interface Status		SIM2 Voltage Select	SIM2 LDO Enable/ Disable	SIM1 Interface Status		SIM1 Voltage Select	SIM1 LDO Enable/ Disable	08h	SIM Interface Control Register	R/W	0000 0000

Table 2. Device Hardware Revision Register (00h)

Device HW Driver Register	Bits(s)	Type (R/W)	Description
HW identification	7:0	R	This register contains the manufacturer and device ID ⁽¹⁾ (value to be specified by the manufacturer)

- (1) The manufacturer ID part of this data shall remain unchanged when the HW revision ID is updated. The manufacturer ID shall uniquely identify the manufacturer. The manufacturer ID is encoded on the MSB nibble.

Table 3. Device Software Revision Register (01h)

Device SW Driver Register	Bits(s)	Type (R/W)	Description
SW Driver Version	7:0	R	This register contains information about the SW driver required for this device. This information shall only be updated when changes to the device requires SW modifications. Initial register value is 00h

Table 4. Status Register (04h)

Status Register	Bits(s)	Type (R/W)	Description
Unused	0	Unused	Unused
Unused	1	Unused	Unused
Unused	2	Unused	Unused
Unused	3	Unused	Unused
SIM1 Interface Status [1:0]	5:4 ⁽¹⁾	R	Status of SIM1 interface '00' Powered down with pull-downs activated '01' Isolated with pull-downs deactivated '10' Powered with pull downs activated '11' Active with pull downs deactivated
SIM2 Interface Status [1:0]	7:6 ⁽¹⁾	R	Status of SIM2 interface '00' Powered down with pull-downs activated '01' Isolated with pull-downs deactivated '10' Powered with pull downs activated '11' Active with pull downs deactivated

- (1) The content of bits 5:4 and 7:6 reflects the value written to the state bits in the SIM Interface control register 3:2 and 7:6 respectively and the setting of the regulator bits in the SIM interface control register 0 and 4 respectively.

Table 5. SIM Interface Control Register (08h)⁽¹⁾⁽²⁾

Status Register	Bit(s)	Type (R/W)	Description
SIM1 Regulator Control	0	R/W	'0' Regulator is off, regulator output is pulled down '1' Regulator is powered on, regulator output pull-down is released
SIM1 Regulator Voltage Selection	1	R/W	'0' 1.8 V '1' 2.95 V
SIM1 Interface State [1:0]	3:2	R/W	Status of SIM1 interface '00' Powered down state with pull-downs activated '01' Isolated state with pull-downs deactivated '10' Not allowed '11' Active state with pull downs deactivated
SIM2 Regulator Control	4	R/W	'0' Regulator is off, regulator output is pulled down '1' Regulator is powered on, regulator output pull-down is released

- (1) Reset value: 00h
 (2) The state '10', on bits 3:2 and 7:6, is not prevented by HW but shall never be set by SW. State '10' means that the interface is powered with the pull-downs active, this state correspond to state '00' with the regulator being switched on. Setting the state to '10' does not have any impact on the corresponding regulator bit setting. The regulator control bits do not impact the state bits in this register. The regulator control bits however do impact the status bits in the status register.

Table 5. SIM Interface Control Register (08h)⁽¹⁾⁽²⁾ (continued)

Status Register	Bit(s)	Type (R/W)	Description
SIM2 Regulator Voltage	5	R/W	'0' 1.8 V '1' 2.95 V
SIM2 Interface State [1:0]	7:6	R/W	Status of SIM2 interface '00' Powered down state with pull-downs activated '01' Isolated state with pull-downs deactivated '10' Not allowed '11' Active state with pull downs deactivated

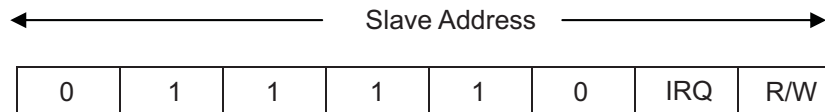
BASIC DEVICE OPERATION

The TXS02324 is controlled through a standard I²C interface reference to VDDIO. It is connected between the two SIM card slots and the SIM/UICC interface of the baseband. The device uses VBAT and VDDIO as supply voltages. The supply voltage for each SIM card is generated by an on-chip low drop out regulator. The interface between the baseband and the TXS02324 is reference to VDDIO while the interface between the TXS02324 and the SIM card is referenced to the LDO output of either VSIM1 or VSIM2 depending on which slot is being selected. The VDDIO on the baseband side normally does not exceed 1.8V, thus voltage level shifting is needed to support a 3V SIM/UICC interface (Class B).

The TXS02324 has two basic states, the reset and operation state. The baseband utilizes information in the status registers to determine how to manipulate the control registers to properly switch between two SIM cards. These fundamental sequences are outlined below and are to help the user to successfully incorporate this device into the system.

DEVICE ADDRESS

The address of the device is shown below:



Address Reference

IRQ @ Reset	R/W	Slave Address
0	0 (W)	120 (decimal), 78(h)
0	1 (R)	121 (decimal), 79(h)
1	0 (W)	122 (decimal), 7A(h)
1	1 (R)	123 (decimal), 7B(h)

RESET STATE

In the reset state the device settings are brought back to their default values and any SIM card that has been active is deactivated. After reset, neither of the UICC/SIM interfaces is selected. The active pull-downs at the UICC/SIM interface are automatically activated. To ensure the system powers up in an operational state, device uses an internal 32 KHz clock for internal timing generation.

- Power up the TXS02324 by asserting VBAT to enter the operation state
- I²C Interface becomes active with the VDDIO supply

RESET summary:

- Any pending interrupts are cleared
- I²C registers are in the default state
- Both on chip regulators are set to 1.8V and disabled
- All SIM1 and SIM2 signals are pulled to GND

SETTING UP THE SIM INTERFACE

The TXS02324 supports both Class C (1.8V) or Class B (2.95V) SIM cards. In order to support these cards types, the interface on the SIM side needs to be properly setup. After power up, the system should default to SIM1 card. The following sequence outlines a rudimentary sequence of preparing the SIM1 card interface:

- Configure the SIM1 regulator to 1.8V by asserting B1 = 0 in the SIM Interface Control Register (08h). The system by default should start in 1.8V mode.
- The baseband SIM interface is set to a LOW state.
- Disable the SIM1 interface by asserting B2 = 0 and B3 = 0 in the SIM Interface Control Register.
- Disable the SIM2 interface by asserting B6 = 0 and B7 = 0 in the SIM Interface Control Register.
- VSIM1 voltage regulator should now be activated by asserting B0 = 1 in the SIM Interface Control Register.
- Enable the SIM1 interface by asserting B2 = 1 and B3 = 1 in the SIM Interface Control Register.
- The SIM1 interface (VSIM1, SIM1CLK, SIM1I/O) is now active. The TXS02324 relies on the baseband to perform the power up sequencing of the SIM card. If there is lack of communication between the baseband and the SIM card, the SIM1 interface must be powered-down and then powered up again through the regulator by configuring it to 2.95V by asserting B1 = 1 in the SIM Interface Control Register.

SWITCHING BETWEEN SIM CARDS

The following sequence outlines a rudimentary sequence of switching between the SIM1 card and SIM2 card:

- Put the SIM1 card interface into “clock stop” mode then assert B2 = 1 and B3 = 0 in the SIM Interface Control Register (08h). This will latch the state of the SIM1 interface (SIM1CLK, SIM1I/O, SIM1RST).
- There can be two scenarios when switching to SIM2 card:
 - SIM2 may be in the power off mode, B6 = 0 and B7 = 0 in the Status Register (04h). If SIM2 is in power off mode, the SIM/UICC interface will need to be set to the power off state. In this case the baseband will most likely need to go through a power up sequence iteration
 - SIM2 may already be in the “clock stop” mode, B6 = 1 and B7 = 0 in the Status Register (04h). If SIM2 is in “clock stop” mode, the interface between the baseband and the device is set to the clock stop mode levels that correspond to the SIM2 card interface.
- After determining whether the SIM2 card is either in power off mode or clock stop mode, the SIM2 card interface is then activated by asserting B6 = 1 and B7 = 1 in the SIM Interface Control Register (08h) and the negotiation between the baseband and card can continue.
- Switching from SIM2 to SIM1 done in the same manner.

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)

Level Translator⁽¹⁾

		MIN	MAX	UNIT	
VDDIO	Supply voltage range	-0.3	4.0	V	
V _I	Input voltage range	V_I/O-port	-0.5	4.6	V
		VSIMx-port	-0.5	4.6	
		Control inputs	-0.5	4.6	
V _O	Voltage range applied to any output in the high-impedance or power-off state	V_I/O-port	-0.5	4.6	V
		VSIMx-port	-0.5	4.6	
V _O	Voltage range applied to any output in the high or low state	V_I/O-port	-0.5	4.6	V
		VSIMx-port	-0.5	4.6	
I _{IK}	Input clamp current	V _I < 0	-50	mA	
I _{OK}	Output clamp current	V _O < 0	-50	mA	
I _O	Continuous output current		±50	mA	
	Continuous current through V _{CCA} or GND		±100	mA	
T _{stg}	Storage temperature range	-65	150	°C	

- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

LDO⁽¹⁾

		MIN	MAX	UNIT
V _{IN}	Input voltage range	-0.3	6	V
V _{OUT}	Output voltage range	-0.3	6	V
T _J	Junction temperature range	-55	150	°C
T _{stg}	Storage temperature range	-55	150	°C
ESD rating	Human-Body Model (HBM)		2	kV
	Charged-Device Model (CDM)		1000	V

- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

THERMAL IMPEDANCE RATINGS

			UNIT
θ_{JA}	Package thermal impedance ⁽¹⁾	RUK package	94.1 °C/W

(1) The package thermal impedance is calculated in accordance with JESD 51-7.

RECOMMENDED OPERATING CONDITIONS⁽¹⁾**Level Translator**

		Description	MIN	MAX	UNIT
VDDIO	Supply voltage		1.7	3.3	V
V _{IH}	High-level input voltage	Applies to pins: RSTX, SCL, SDA, IRQ, SIMRST, SIMCLK, SIMIO	VDDIO × 0.7	1.9	V
V _{IL}	Low-level input voltage		0	VDDIO × 0.3	V
$\Delta t/\Delta v$	Input transition rise or fall rate			5	ns/V
T _A	Operating free-air temperature		–40	85	°C

(1) All unused data inputs of the device must be held at V_{CCI} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

ELECTRICAL CHARACTERISTICS

Level Translator

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	VDDIO	VSIM1	VSIM2	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{OH}	SIM1RST	I _{OH} = -100 μA Push-Pull	1.7 V to 3.3 V	1.8 V / 2.95 V (Supplied by LDO)	1.8 V / 2.95 V (Supplied by LDO)	VSIM1 × 0.8		V	
	SIM1CLK					VSIM1 × 0.8			
	SIM1IO	I _{OH} = -10 μA Open-Drain				VSIM1 × 0.8			
	SIM2RST	I _{OH} = -100 μA Push-Pull				VSIM2 × 0.8			
	SIM2CLK					VSIM2 × 0.8			
	SIM2IO	I _{OH} = -10 μA Open-Drain				VSIM2 × 0.8			
	SIMIO	I _{OH} = -10 μA Open-Drain				VDDIO × 0.8			
V _{OL}	SIM1RST	I _{OL} = 1 mA Push-Pull	1.7 V to 3.3 V	1.8 V / 2.95 V (Supplied by LDO)	1.8 V / 2.95 V (Supplied by LDO)	VSIM1 × 0.2		V	
	SIM1CLK	I _{OL} = 1 mA Push-Pull				VSIM1 × 0.2			
	SIM1IO	I _{OL} = 1 mA Open-Drain				0.3			
	SIM2RST	I _{OL} = 1 mA Push-Pull				VSIM2 × 0.2			
	SIM2CLK	I _{OL} = 1 mA Push-Pull				VSIM2 × 0.2			
	SIM2IO	I _{OL} = 1 mA Open-Drain				0.3			
	SIMIO	I _{OL} = 1 mA Open-Drain				0.3			
I _i	Control inputs	V _i = OE	1.7 V to 3.3 V	1.8 V / 2.95 V (Supplied by LDO)	1.8 V / 2.95 V (Supplied by LDO)	±1		μA	
I _{CC I/O}		V _i = V _{CCI} I _o = 0	1.7 V to 3.3 V	1.8 V / 2.95 V (Supplied by LDO)	1.8 V / 2.95 V (Supplied by LDO)	±5		μA	
C _{io}	SIM_I/O port					7		pF	
	SIMx port					4			
C _i	Control inputs	V _i = V _{I/O} or GND				3		pF	
	Clock input								

 (1) All typical values are at T_A = 25°C.

ELECTRICAL CHARACTERISTICS LDO (Control Input Logic = High)

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{BAT}	Input voltage		2.3		5.5	V
V _{OUT}	Output voltage	Class-B Mode	2.82	2.95	3.18	V
		Class-C Mode	1.65	1.8	1.95	
V _{DO}	Dropout voltage	I _{OUT} = 50 mA			100	mV
I _{GND}	Ground-pin current	I _{OUT} = 0 mA			35	μA
		I _{OUT} = 50 mA			150	
I _{SHDN}	Shutdown current (I _{GND})	V _{ENx} ≤ 0.4 V, (V _{SIMx} + V _{DO}) ≤ V _{BAT} ≤ 5.5 V, T _J = 85°C			3	μA
I _{OUT(SC)}	Short-circuit current	R _L = 0 Ω			400	mA
C _{OUT}	Output Capacitor			1		μF
PSRR	Power-supply rejection ratio	V _{BAT} = 3.25 V, V _{SIMx} = 1.8 V or 3 V, C _{OUT} = 1 μF, I _{OUT} = 50 mA	f = 1 kHz	50		dB
			f = 10 kHz	40		
T _{STR}	Start-up time	V _{SIMx} = 1.8 V or 3 V, I _{OUT} = 10 mA, C _{OUT} = 1 μF			50	μS
T _J	Operating junction temperature		−40		85	°C

(1) All typical values are at T_A = 25°C.

GENERAL ELECTRICAL CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Hyst	Internal hysteresis of comparator			±50		mV
R _{SIMPU}	SIM I/O pull-up			20		kΩ
R _{SIMxPU}	SIMx I/O pull-up	Class B		7.5		kΩ
		Class C		4.5		
R _{SIMPD}	SIMx I/O pull-down	Active pull-downs are connected to the V _{SIM1/2} regulator output to the SIM1/2 CLK, SIM1/2 RST, SIM1/2 I/O when the respective regulator is disabled		2		kΩ

SWITCHING CHARACTERISTICS
VSIMx = 1.8 V or 2.95 V Supplied by Internal LDO, VBAT = 2.3V to 5.5V

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{I/O} = 1.7 V to 3.3 V		UNIT
		TYP		
t _{rA} Baseband side to SIM side	SIMIO	Open Drain	210	ns
	SIMRST	Push Pull	4.3	ns
	SIMCLK	Push Pull	4	ns
t _{rA} Baseband side to SIM side	SIMxIO	Open Drain	16	ns
	SIMRST	Push Pull	4	ns
	SIMxCLK	Push Pull	5	ns
t _{rB} SIM side to Baseband side	SIMxIO	Open Drain	210	ns
t _{rB} SIM side to Baseband side	SIMxIO	Open Drain	6	ns
f _{max}	SIMxCLK	Push Pull	5	MHz
t _{PLH}	SIMCLK to SIMxCLK	Push Pull	8	ns
	SIMRST to SIMxRST	Push Pull	8	ns
	SIMIO to SIMxIO	Open Drain	260	ns
	SIMxIO to SIMIO	Open Drain	260	ns
t _{PHL}	SIMCLK to SIMxCLK	Push Pull	7	ns
	SIMRST to SIMxRST	Push Pull	7	ns
	SIMIO to SIMxIO	Open Drain	23	ns
	SIMxIO to SIMIO	Open Drain	23	ns

OPERATING CHARACTERISTICS

$T_A = 25^\circ\text{C}$, $V_{\text{SIMx}} = 1.8\text{ V}$ for Class C, $V_{\text{SIMx}} = 2.95\text{ V}$ for Class B

PARAMETER		TEST CONDITIONS	TYP	UNIT
C_{pd} ⁽¹⁾	Class B	$C_L = 0$, $f = 5\text{ MHz}$, $t_r = t_f = 1\text{ ns}$	11	pF
	Class C		9.5	

(1) Power dissipation capacitance per transceiver

APPLICATION INFORMATION

The LDO's included on the TXS02324 achieve ultra-wide bandwidth and high loop gain, resulting in extremely high PSRR at very low headroom ($V_{BAT} - V_{SIM1/2}$). The TXS02324 provides fixed regulation at 1.8V or 2.95V. Low noise, enable (through I²C control), low ground pin current make it ideal for portable applications. The device offers sub-bandgap output voltages, current limit and thermal protection, and is fully specified from –40°C to +85°C.

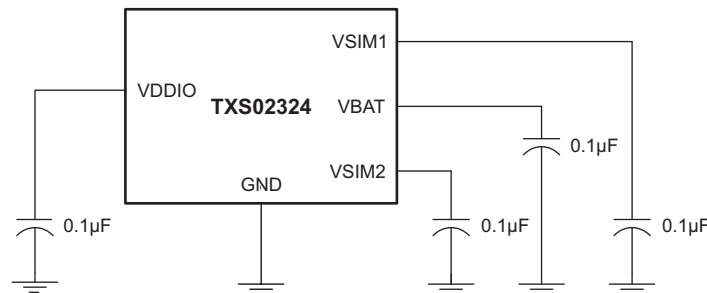


Figure 2. Typical Application circuit for TXS02324

Input and Output Capacitor Requirements

It is good analog design practice to connect a 1.0 µF low equivalent series resistance (ESR) capacitor across the input supply (VBAT) near the regulator. Also, a 0.1µF is required for the logic core supply (VDDIO).

This capacitor will counteract reactive input sources and improve transient response, noise rejection, and ripple rejection. A higher-value capacitor may be necessary if large, fast rise-time load transients are anticipated or if the device is located several inches from the power source. The LDO's are designed to be stable with standard ceramic capacitors of values 1.0 µF or larger. X5R- and X7R-type capacitors are best because they have minimal variation in value and ESR over temperature. Maximum ESR should be < 1.0 Ω.

Output Noise

In most LDO's, the bandgap is the dominant noise source. To improve ac performance such as PSRR, output noise, and transient response, it is recommended that the board be designed with separate ground planes for V_{IN} and V_{OUT} , with each ground plane connected only at the GND pin of the device. In addition, the ground connection for the bypass capacitor should connect directly to the GND pin of the device.

Internal Current Limit

The TXS02324 internal current limit helps protect the regulator during fault conditions. During current limit, the output sources a fixed amount of current that is largely independent of output voltage. For reliable operation, the device should not be operated in a current limit state for extended periods of time.

The PMOS pass element in the TXS02324 has a built-in body diode that conducts current when the voltage at $V_{SIM1/2}$ exceeds the voltage at V_{BAT} . This current is not limited, so if extended reverse voltage operation is anticipated, external limiting may be appropriate.

Dropout Voltage

The TXS02324 uses a PMOS pass transistor to achieve low dropout. When ($V_{BAT} - V_{SIM1/2}$) is less than the dropout voltage (V_{DO}), the PMOS pass device is in its linear region of operation and the input-to-output resistance is the $R_{DS(ON)}$ of the PMOS pass element. V_{DO} will approximately scale with output current because the PMOS device behaves like a resistor in dropout.

Startup

The TXS02324 uses a quick-start circuit which allows the combination of very low output noise and fast start-up times. Note that for fastest startup, V_{BATT} should be applied first, and then enabled by asserting the I²C register.

Transient Response

As with any regulator, increasing the size of the output capacitor reduces over/undershoot magnitude but increases duration of the transient response.

Minimum Load

The TXS02324 is stable and well-behaved with no output load. Traditional PMOS LDO regulators suffer from lower loop gain at very light output loads. The TXS02324 employs an innovative low-current mode circuit to increase loop gain under very light or no-load conditions, resulting in improved output voltage regulation performance down to zero output current.

THERMAL INFORMATION

Thermal Protection

Thermal protection disables the output when the junction temperature rises to approximately +160°C, allowing the device to cool. When the junction temperature cools to approximately +140°C the output circuitry is again enabled. Depending on power dissipation, thermal resistance, and ambient temperature, the thermal protection circuit may cycle on and off. This cycling limits the dissipation of the regulator, protecting it from damage because of overheating.

Any tendency to activate the thermal protection circuit indicates excessive power dissipation or an inadequate heat sink. For reliable operation, junction temperature should be limited to +85°C maximum. To estimate the margin of safety in a complete design (including heat sink), increase the ambient temperature until the thermal protection is triggered; use worst-case loads and signal conditions. For good reliability, thermal protection should trigger at least +35°C above the maximum expected ambient condition of your particular application. This configuration produces a worst-case junction temperature of +85°C at the highest expected ambient temperature and worst-case load.

The internal protection circuitry of the TXS02324 has been designed to protect against overload conditions. It was not intended to replace proper heat sinking. Continuously running the TXS02324 into thermal shutdown will degrade device reliability.

TYPICAL CHARACTERISTICS

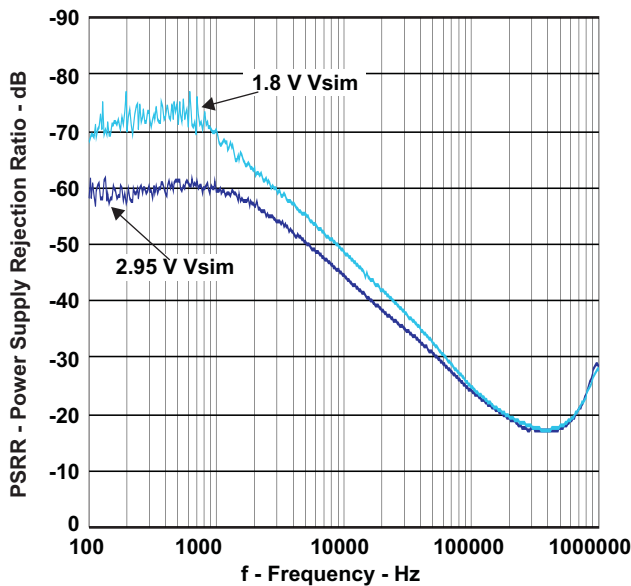


Figure 3. PSRR

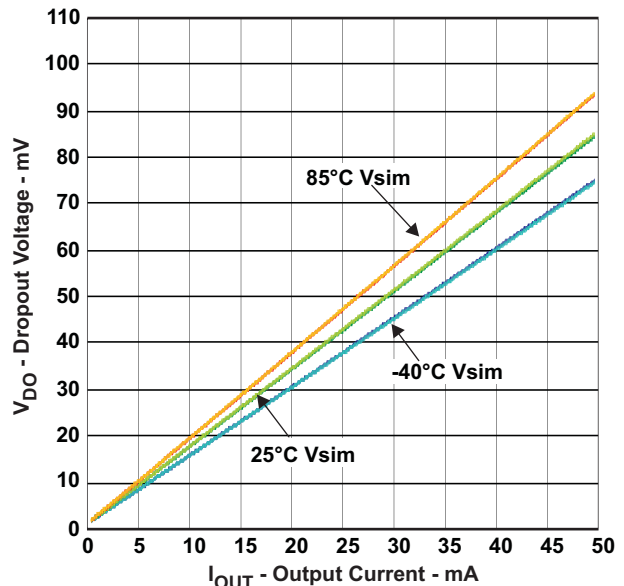


Figure 4. Dropout Voltage vs Output Current

TYPICAL CHARACTERISTICS (continued)

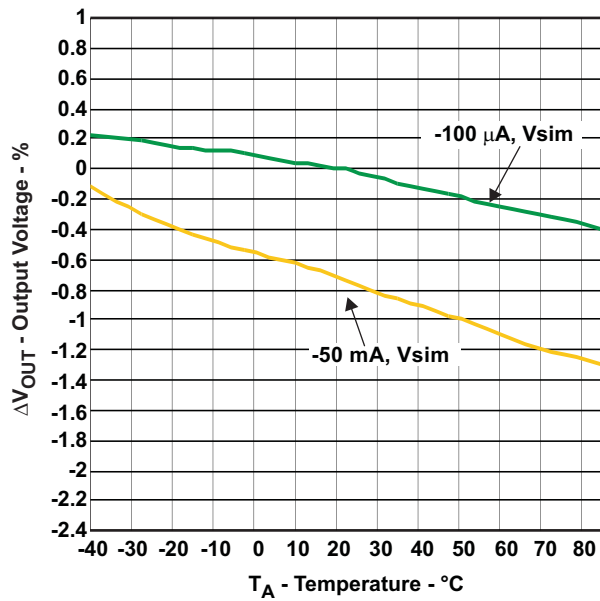


Figure 5. Output Voltage vs Temperature, Class-B/C

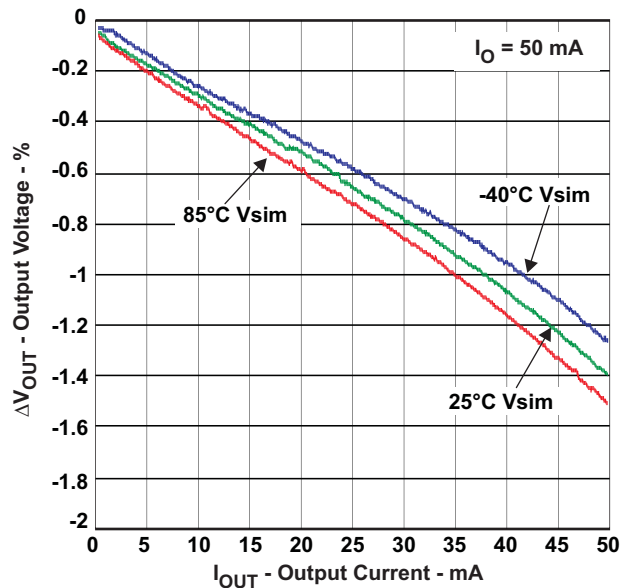


Figure 6. Load Regulation, Iout = 50 mA, Class-C

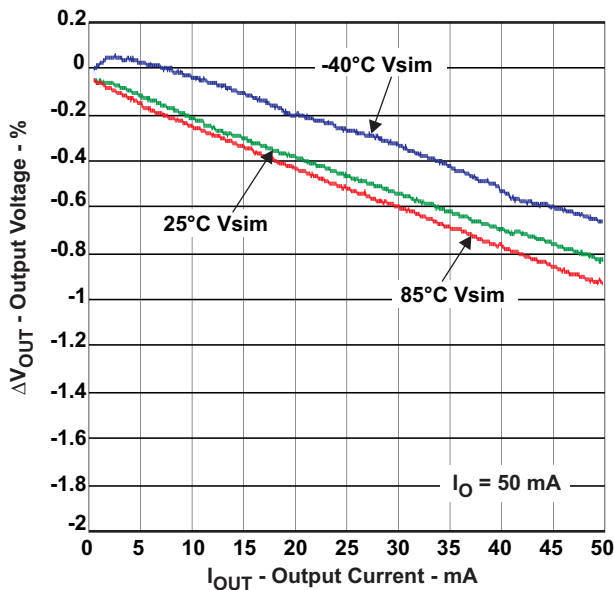


Figure 7. Load Regulation, Iout = 50 mA, Class-B

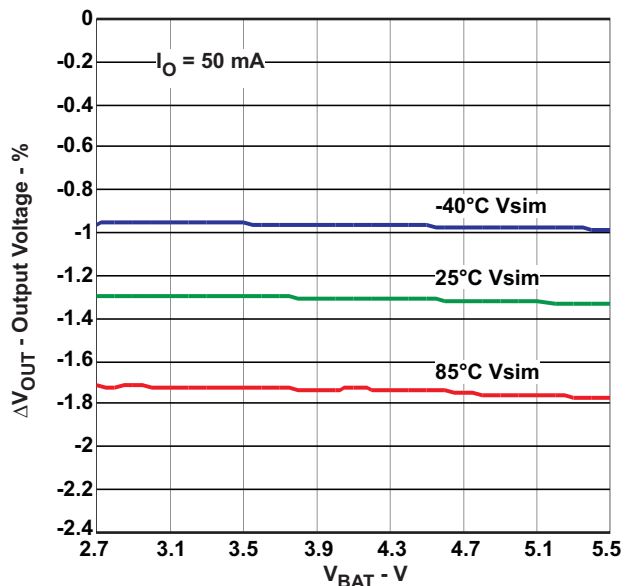


Figure 8. Line Regulation, Iout = 50 mA, Class-C

TYPICAL CHARACTERISTICS (continued)

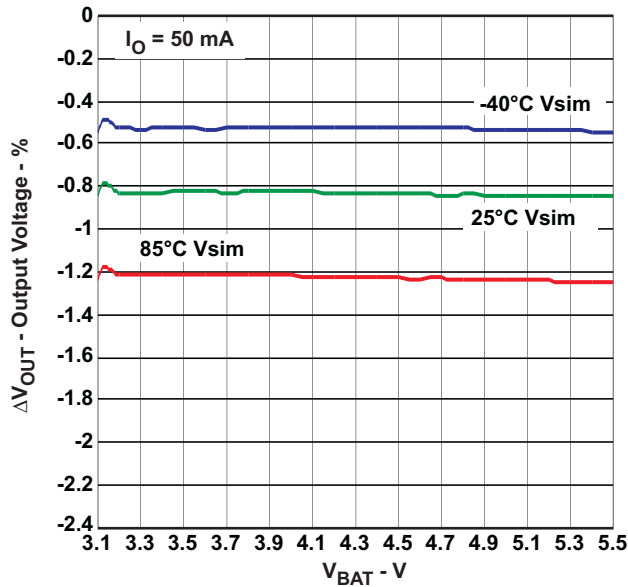


Figure 9. Line Regulation, $I_{out} = 50 \text{ mA}$, Class-B

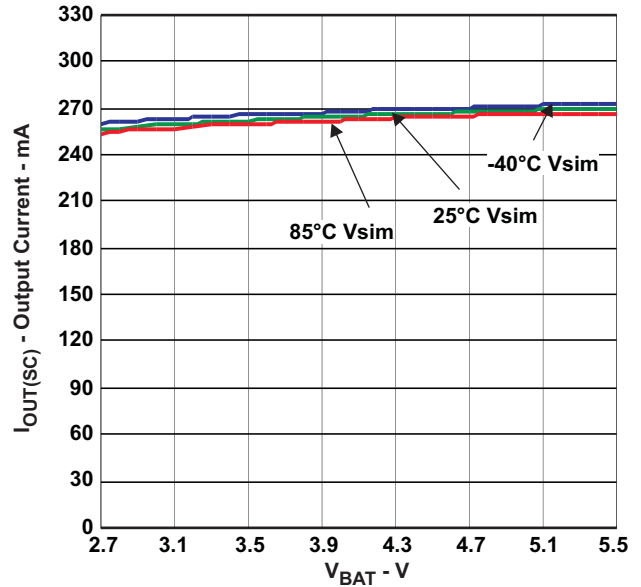


Figure 10. Current Limit vs Input Voltage, Class-B/C

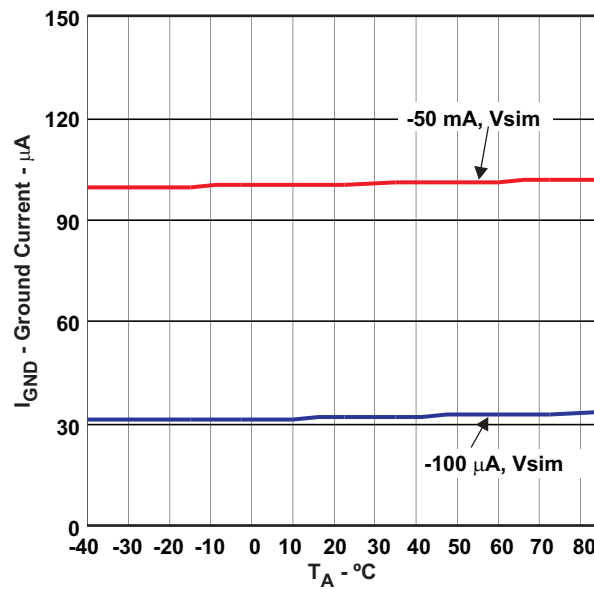


Figure 11. Ground Current vs Temperature, Class-C

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